

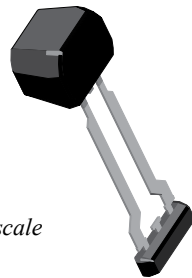
Vibration-Tolerant Hall-Effect Transmission Speed and Direction Gear Tooth Sensor IC

FEATURES AND BENEFITS

- **Differential Hall-effect sensor** measures ferrous targets with inherent stray field immunity
- **SolidSpeed Digital Architecture** provides robust, adaptive performance with advanced algorithms that provide vibration immunity over the full target pitch
- **Integrated solution** includes a back-bias magnet and capacitor in a single overmolded package
- **ASIL-Compliant:** ASIL B safety element out-of-context (SEooC) developed in accordance with ISO 26262, when used as specified in the safety manual
 - Integrated diagnostics and certified safety design process
- **Two-wire current source output** pulse-width protocol supporting speed, direction, and ASIL error reporting
- **EEPROM** enables factory traceability



PACKAGE: 3-pin SIP (suffix SN)



Not to scale

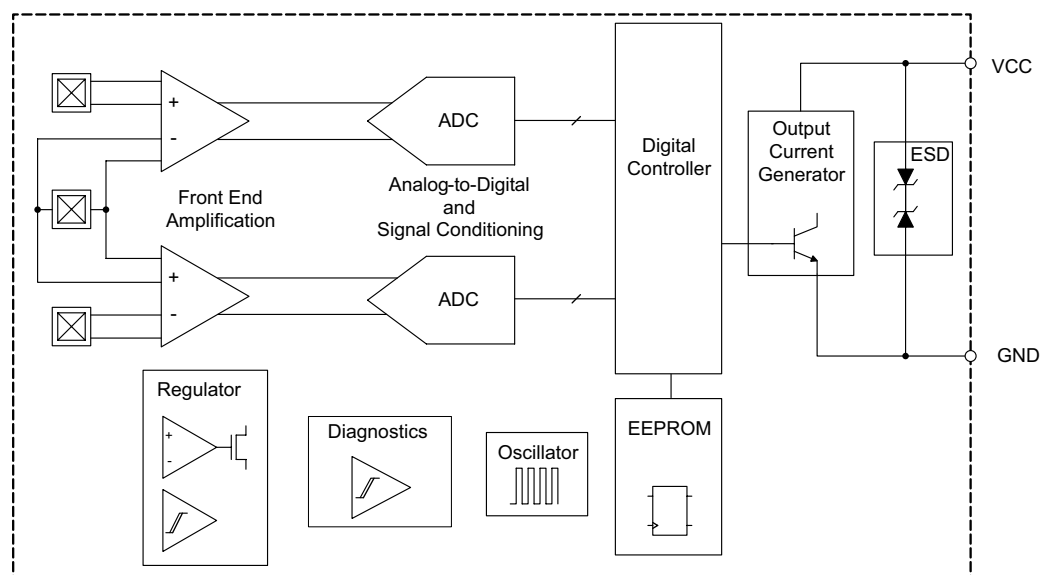
DESCRIPTION

The ATS19520 is an advanced Hall-effect integrated circuit (IC) that uses an integrated back-bias magnet to measure the speed and direction of rotating ferrous targets. The package features an integrated capacitor for electromagnetic compatibility (EMC).

The ATS19520 employs intelligent algorithms that allow stable operation during vibration and highly dynamic air gap environments common to transmission applications. In addition, the differential sensing offers inherent rejection of interfering common-mode magnetic fields.

The ATS19520 was developed in accordance with ISO 26262 as a hardware safety element out of context with ASIL B capability for use in automotive safety-related systems when integrated and used in the manner prescribed in the applicable safety manual and datasheet.

The ATS19520 is provided in a 3-pin SIP package (suffix SN) that is lead (Pb) free, with tin leadframe plating. The SN package includes an IC, magnet, and capacitor integrated into a single overmold, with an additional molded lead-stabilizing bar for robust shipping and ease of assembly.



Functional Block Diagram

Vibration-Tolerant Hall Effect Transmission Speed and Direction Gear Tooth Sensor IC

Ⓟ

* Not all combinations are available. Contact Allegro sales for availability and pricing of custom programming options.



ATS19520

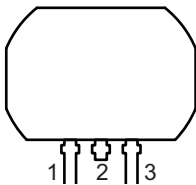
Vibration-Tolerant Hall Effect
Transmission Speed and Direction Gear Tooth Sensor IC

SPECIFICATIONS

ABSOLUTE MAXIMUM RATINGS

Characteristic	Symbol	Notes	Rating	Units
Supply Voltage	V_{CC}	Refer to Power Derating section	28	V
Reverse Supply Voltage	V_{RCC}		−18	V
Operating Ambient Temperature	T_A	Range L	−40 to 150	°C
Maximum Junction Temperature	$T_{J(max)}$		165	°C
Storage Temperature	T_{stg}		−65 to 170	°C

PINOUT DIAGRAM AND TERMINAL LIST



Package SN, 3-Pin SIP Pinout Diagram

Terminal List Table

Number	Name	Function
1	VCC	Supply voltage
2	VCC	Supply voltage
3	GND	Ground

Internal Discrete Capacitor Ratings

Characteristic	Symbol	Notes		Rating	Units
Nominal Capacitance	C _{SUPPLY}	Connected between VCC and GND; refer to Figure 1	B	10	nF
			L	22	nF

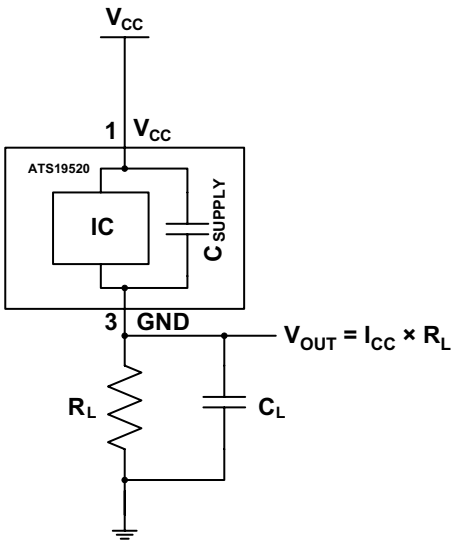


Figure 1: Typical Application Circuit

OPERATING CHARACTERISTICS: Valid throughout full operating and temperature ranges, unless otherwise specified

Characteristic	Symbol	Test Conditions	Min.	Typ. [1]	Max.	Unit	
GENERAL							
Supply Voltage [2]	V _{CC}	Operating, T _J < T _{J(max)} ; voltage across pin 1 and pin 3; does not include voltage across R _L	4	–	24	V	
Undervoltage Lockout	V _{CC(UV)}	V _{CC} 0 V → 5 V or 5 V → 0 V	–	3.6	3.95	V	
Reverse Supply Current [3]	I _{RCC}	V _{CC} = V _{RCC(max)}	–10	–	–	mA	
Supply Current	I _{CC(LOW)}	Low-current state	5.9	7	8	mA	
	I _{CC(HIGH)}	High-current state	12	14	16	mA	
	I _{CC(HIGH)} / I _{CC(LOW)}	Ratio of high current to low current (isothermal)	1.9	–	–	–	
ASIL Safety Current	I _{RESET}	Refer to Figure 11	1.5	–	3.9	mA	
PROTECTION CIRCUITS							
Supply Zener Clamp Voltage	V _{Zsupply}	I _{CC} = 19 mA, T _A = 25°C	28	–	–	V	
POWER-ON CHARACTERISTICS							
Power-On State	POS	V _{CC} > V _{CC(min)} , as connected in Figure 1	I _{CC(LOW)}			mA	
Power-On Time [4]	t _{PO}	Time from V _{CC} > V _{CC(min)} , until device has entered calibration	–	–	1	ms	
OUTPUT PULSE CHARACTERISTICS, PULSE PROTOCOL [5]							
Output Rise Time	t _r	Voltage measured at pin 2 in Figure 1, R _L = 100 Ω, C _L = 10 pF, measured between 10% and 90% of signal	SNL variant	0	4.5	8	μs
			SNB variant	0	2	4	μs
Output Fall Time	t _r	Voltage measured at pin 3 in Figure 1, R _L = 100 Ω, C _L = 10 pF, measured between 10% and 90% of signal	SNL variant	0	4.5	8	μs
			SNB variant	0	2	4	μs
Pulse Width, ASIL Warning	t _{w(ASILwarn)}	Refer to Figure 11	63	–	121	μs	
Pulse Width, ASIL Critical	t _{w(ASILcrit)}	Refer to Figure 11	4	–	8	ms	

Continued on next page...

OPERATING CHARACTERISTICS (continued): Valid throughout full operating temperature ranges,
unless otherwise specified

Characteristic	Symbol	Test Conditions	Min.	Typ. [1]	Max.	Unit
INTERMEDIATE PULSE WIDTH OPTION (PART NUMBER -xxlxxxx)						
Threshold to Enter High-Speed Mode	f_{HIGH}	T_{CYCLE} frequency increasing	0.935	1.1	1.265	kHz
Threshold to Exit High-Speed Mode	f_{LOW}	T_{CYCLE} frequency decreasing	0.85	1	1.15	kHz
Pulse Width, Forward Rotation	$t_{w(FWD)}$	T_{CYCLE} frequency < f_{LOW}	51	60	69	μs
Pulse Width, Reverse Rotation	$t_{w(REV)}$	T_{CYCLE} frequency < f_{LOW}	102	120	138	μs
Pulse Width, High-Speed	$t_{w(HS)}$	T_{CYCLE} frequency > f_{HIGH}	25	30	35	μs
Pulse Width, Non-Direction	$t_{w(ND)}$		25	30	35	μs
Operating Frequency, Forward Rotation [6][7]	f_{FWD}		0	–	12	kHz
Operating Frequency, Reverse Rotation [6][7]	f_{REV}		0	–	12	kHz
Operating Frequency, Non-Direction Pulses [6][7]	f_{ND}		0	–	12	kHz
NARROW PULSE WIDTH OPTION (PART NUMBER -xxNxxxx)						
Pulse Width, Forward Rotation	$t_{w(FWD)}$		38	45	52	μs
Pulse Width, Reverse Rotation	$t_{w(REV)}$		76	90	104	μs
Pulse Width, Non-Direction	$t_{w(ND)}$		153	180	207	μs
Operating Frequency, Forward Rotation [6]	f_{FWD}		0	–	12	kHz
Operating Frequency, Reverse Rotation [6]	f_{REV}		0	–	7	kHz
Operating Frequency, Non-Direction Pulses [6]	f_{ND}		0	–	4	kHz
WIDE PULSE WIDTH OPTION (PART NUMBER -xxWxxxx)						
Pulse Width, Forward Rotation	$t_{w(FWD)}$		38	45	52	μs
Pulse Width, Reverse Rotation	$t_{w(REV)}$		153	180	207	μs
Pulse Width, Non-Direction	$t_{w(ND)}$		306	360	414	μs
Operating Frequency, Forward Rotation [6]	f_{FWD}		0	–	12	kHz
Operating Frequency, Reverse Rotation [6]	f_{REV}		0	–	4	kHz
Operating Frequency, Non-Direction Pulses [6]	f_{ND}		0	–	2.2	kHz

Continued on next page...

OPERATING CHARACTERISTICS (continued): Valid throughout full operating temperature ranges, unless otherwise specified

Characteristic	Symbol	Test Conditions	Min.	Typ. [1]	Max.	Unit
INPUT CHARACTERISTICS AND PERFORMANCE						
Air Gap Range		Using Allegro 60-0 reference target; tested at 1000 rpm [8]	0.5	–	2.8	mm
User-Induced Offset		Differential Magnitude valid for both differential magnetic channels.	–400	–	400	G
Operate Point	B _{OP}	% of peak-to-peak IC-processed signal	–	75	–	%
Release Point	B _{RP}	% of peak-to-peak IC-processed signal	–	25	–	%
Switch Point Separation	B _{DIFF(SP-SEP)}	Required amount of amplitude separation between channels at each B _{OP} and B _{RP} occurrence; refer to Figure 4	20	–	–	%B _{DIFF(pk-pk)}
Allowable Differential Sequential Signal Variation	B _{SEQ(n+1)} / B _{SEQ(n)}	Signal cycle-to-cycle variation (refer to Figure 2)	0.7	–	1.3	–
	B _{SEQ(n+i)} / B _{SEQ(n)}	Overall signal variation (refer to Figure 2)	0.1	–	–	–
Initial Calibration	T _{CAL}	Periods after t _{PO} completed and first valid speed and direction output. Constant direction of rotation. Refer to Figure 3 for definition of T _{CYCLE} .	–	–	4 × T _{CYCLE}	–
Vibration Immunity (Startup)			1 × T _{CYCLE}	–	–	–
Vibration Immunity (Running Mode)			1 × T _{CYCLE}	–	–	–
First Direction-Pulse Output Following Direction Change		High Vibration (-xxxHxxxx variant)	–	–	3 × T _{CYCLE}	–
		Low Vibration (-xxLxxxx variant)	–	–	1.5 × T _{CYCLE}	–
First Direction-Pulse Output Following Running Mode Vibration			–	–	3.5 × T _{CYCLE}	–
THERMAL CHARACTERISTICS						
Package Thermal Resistance [9]	R _{θJA}	Single-layer PCB with copper limited to solder pads	–	150	–	°C/W

[1] Typical values are at T_A = 25°C and V_{CC} = 12 V. Performance may vary for individual units, within the specified maximum and minimum limits.

[2] Maximum voltage must be adjusted for power dissipation and junction temperature; see representative for Power Derating discussions.

[3] Negative current is defined as conventional current coming out of (sourced from) the specified device terminal.

[4] Output transients prior to t_{PO} should be ignored.

[5] Timing from start of rising output transition. Measured pulse width will vary on load circuit configurations and thresholds. Pulse width measured at threshold of (I_{CC(HIGH)} + I_{CC(LOW)}) / 2 for non-ASIL pulses and (I_{RESET} + I_{CC(LOW)}) / 2 for ASIL pulses.

[6] Maximum Operating Frequency is determined by satisfactory separation of output pulses. If shorter low-state durations can be resolved, the maximum f_{REV} and f_{ND} may be higher. Does not apply to -xxlxxxx variant or f_{FWD}.

[7] Direction information is not available when frequency > f_{HIGH} for the Intermediate Pulse Width option.

[8] Speed-related effects on maximum air gap are highly dependent upon specific target geometry. Consult with Allegro field applications engineering for aid with assessment of target geometries.

[9] Additional thermal information is available on the Allegro website.

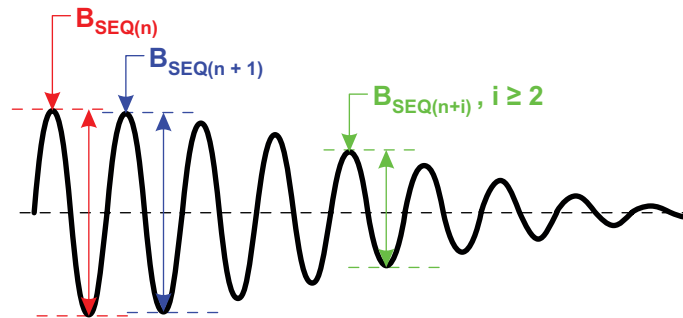
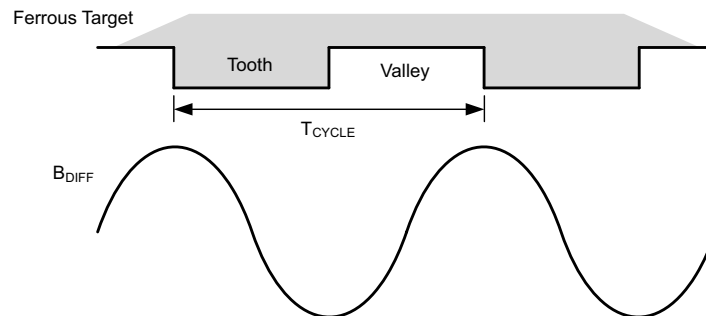


Figure 2: Differential Signal Variation



T_{CYCLE} = Target Cycle; the amount of rotation that moves one tooth and valley across the sensor.

B_{DIFF} = The differential magnetic flux density sensed by the sensor.

Figure 3: Definition of T_{CYCLE}

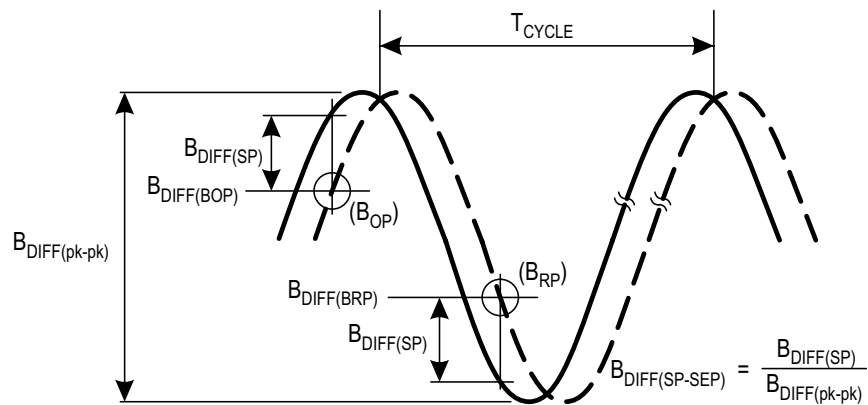
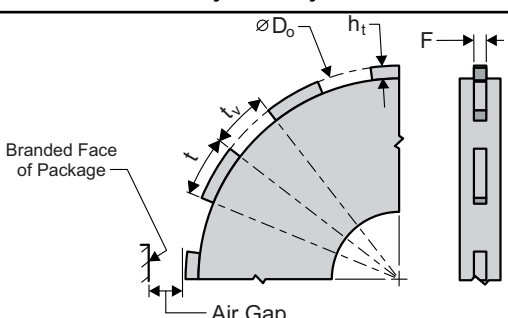
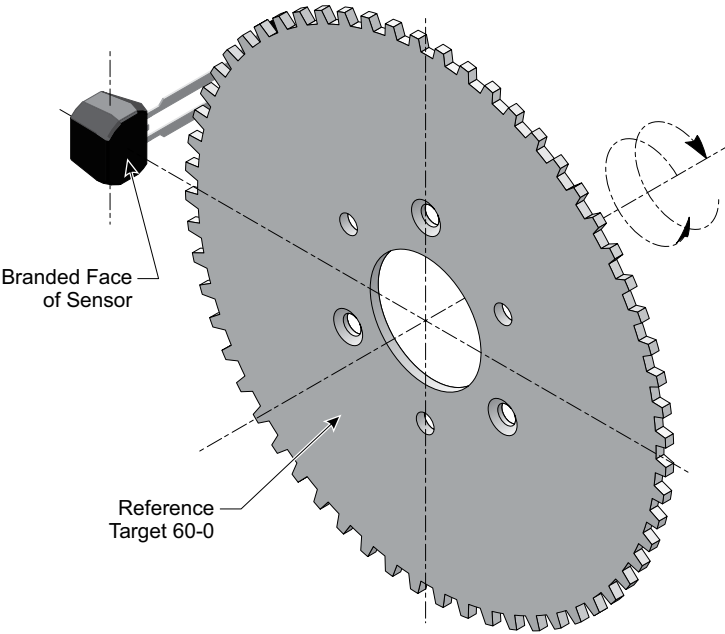


Figure 4: Definition of Switch Point Separation

Reference Target 60-0 (60 Tooth Target)

Characteristics	Symbol	Test Conditions	Typ.	Units	Symbol Key
Outside Diameter	D_o	Outside diameter of target	120	mm	
Face Width	F	Breadth of tooth, with respect to branded face	6	mm	
Circular Tooth Length	t	Length of tooth, with respect to branded face	3	deg.	
Circular Valley Width	t_v	Length of valley, with respect to branded face	3	deg.	
Tooth Whole Depth	h_t		3	mm	
Material		Low Carbon Steel	–	–	



FUNCTIONAL DESCRIPTION

Sensing Technology

The sensor IC contains a single-chip Hall-effect circuit that supports a trio of Hall elements. These are used in differential pairs to provide electrical signals containing information regarding edge position and direction of target rotation. The ATS19520 is intended for use with ferrous targets.

After proper power is applied to the sensor IC, it is capable of providing digital information that is representative of the magnetic features of a rotating target. The waveform diagrams in Figure 5 present the automatic translation of the target profiles, through their induced magnetic profiles, to the digital output signal of the sensor IC.

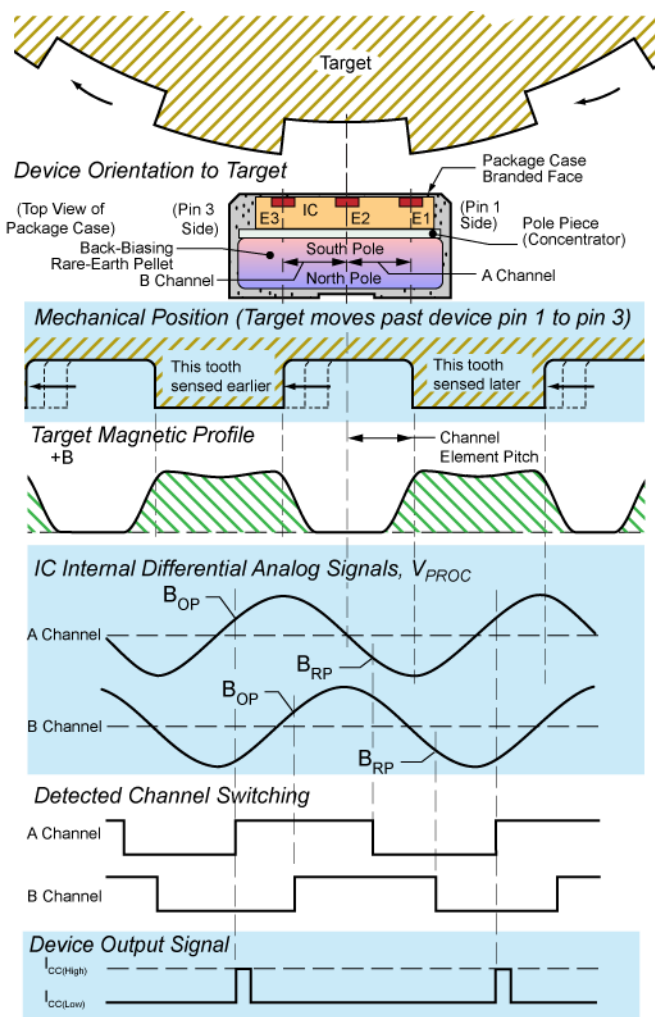


Figure 5: Magnetic Profile

The magnetic profile reflects the features of the target, allowing the sensor IC to present an accurate digital output.

Direction Detection

The sensor IC compares the relative phase of its two differential channels to determine which direction the target is moving. The relative switching order is used to determine the direction, which is communicated through the output protocol.

Data Protocol Description

When a target passes in front of the device (opposite the branded face of the package case), the ATS19520 generates an output pulse for each tooth of the target. Speed information is provided by the output pulse rate, while direction of target rotation is provided by the duration of the output pulses. The sensor IC can sense target movement in both the forward and reverse directions.

FORWARD ROTATION

As shown in panel A in Figure 6, when the target is rotating such that a tooth near the sensor IC – of -Fxxxxxx variant – passes from pin 1 to pin 3, this is referred to as forward rotation. This direction is opposite for the -Rxxxxxx variant. Forward rotation is indicated by output pulse widths of $t_{w(FWD)}$.

REVERSE ROTATION

As shown in panel B in Figure 6, when the target is rotating such that a tooth passes from pin 3 to pin 1, it is referred to as reverse rotation for the -Fxxxxxx variant. Reverse rotation is indicated by output pulse widths of $t_{w(REV)}$.

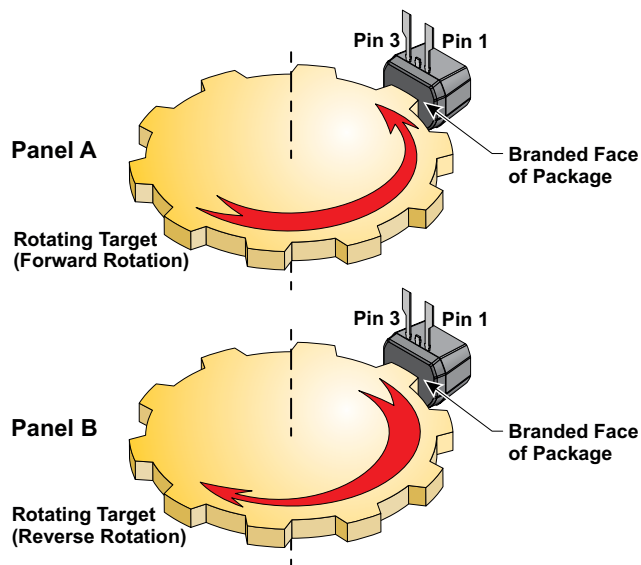


Figure 6: Target Rotation (F Variant Shown)

Startup Detection/Calibration

After proper supply voltage is applied to the IC, the IC detects the magnetic profile of the rotating target.

The calibration period occurs on the first few features of the target that pass in front of the IC.

Direction information is available after calibration is complete.

The locations where the first output edges may occur are shown in Figure 7 and Figure 8 for various starting target phases.

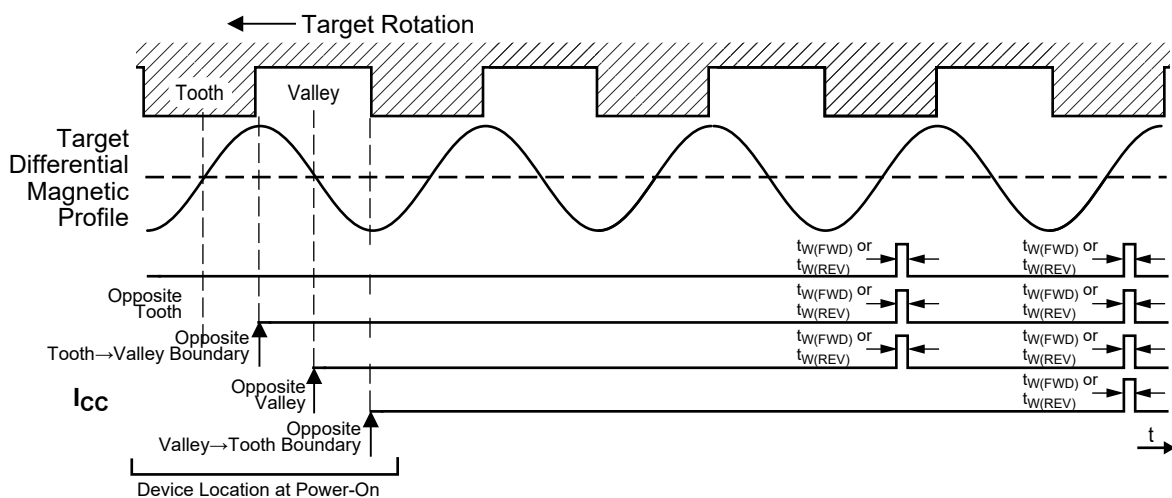


Figure 7: Startup Position Effect on First Device Output Switching (-xxxxxOxx variant)

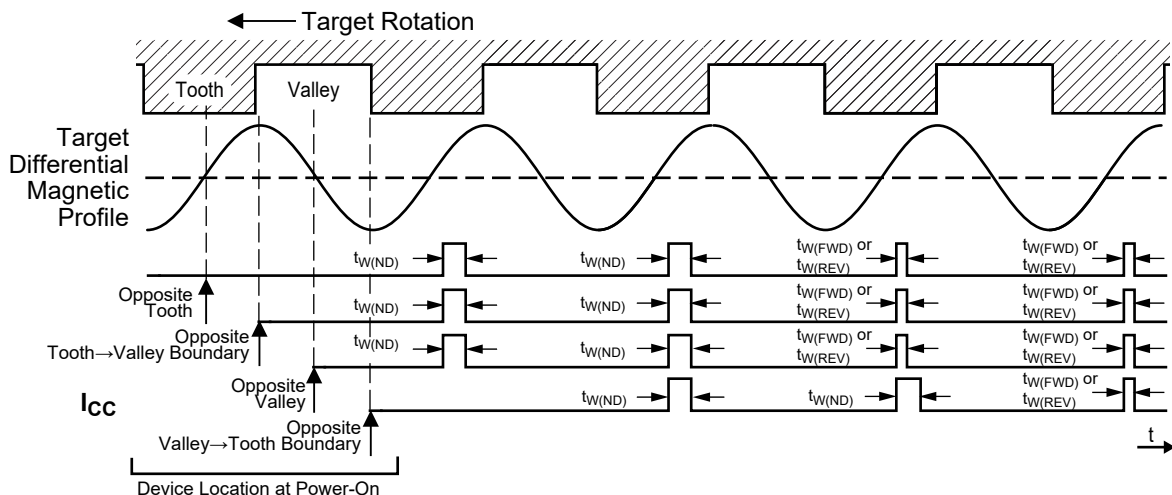


Figure 8: Startup Position Effect on First Device Output Switching (-xxxxxYxx variant)

Vibration Immunity and Direction Detection

Algorithms embedded in the ICs digital controller detect the presence of target vibrations (oscillations) and direction changes through analysis of magnetic input signals.

The advanced detection algorithm provides robust vibration immunity. With the high vibration immunity variant, the vibration algorithm is activated upon the first detected direction change and/

or vibration event that is less than the specified vibration immunity. The IC suppresses direction output and does not resume normal operation until constant direction data is verified.

With the low vibration immunity variant, additionally, the IC reports the first direction change immediately to output.

As shown in Figure 9, the -P option might produce nondirectional pulses during a vibration event, depending on the signal amplitude.

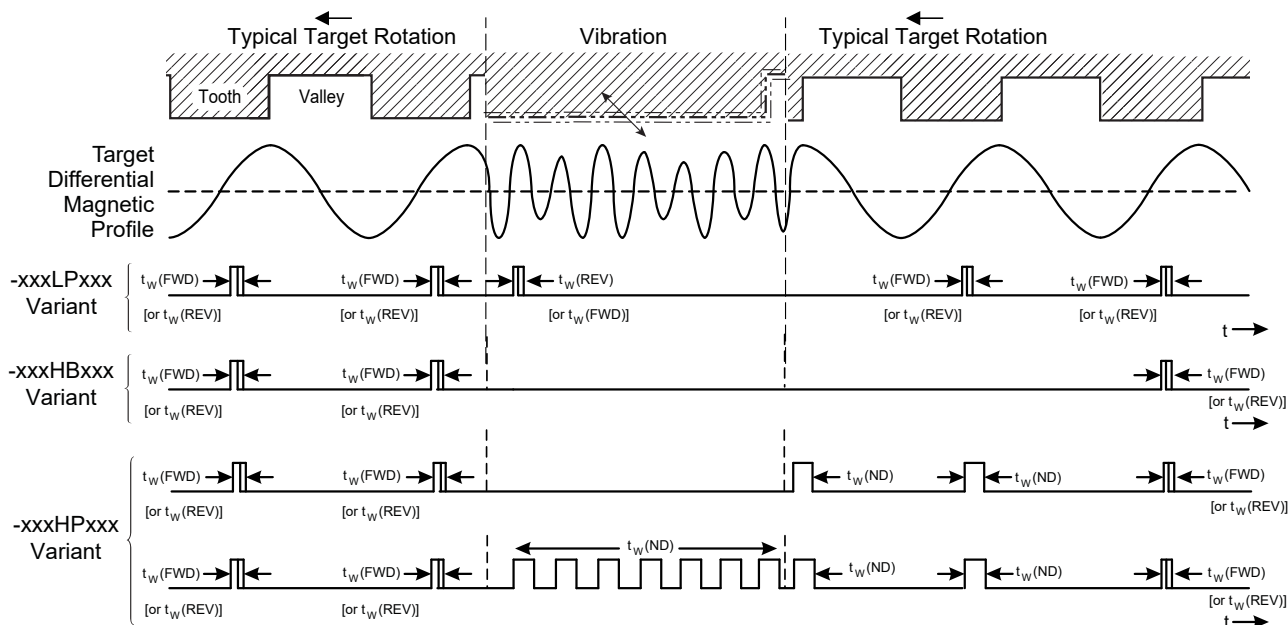


Figure 9: Output Functionality in the Presence of Running-Mode Target Vibration

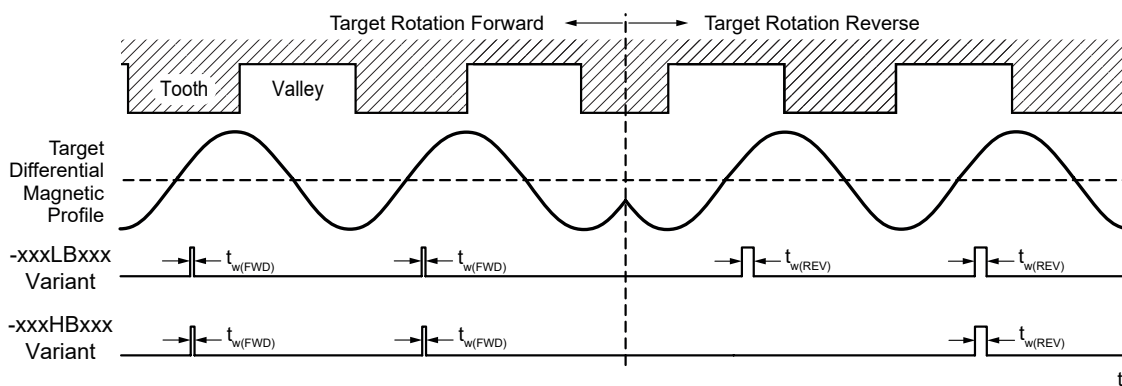


Figure 10: Direction-Change Behavior

ASIL Protocol

The -xxxxxxx-A variant contains diagnostic circuitry that will continuously monitor occurrences of failure defects within the IC. Refer to Figure 11 for the output protocol of the ASIL Safe State after an internal defect has been detected. Error Protocol will result from faults which cause incorrect signal transmission (i.e., too few or too many output pulses).

Note: If a fault exists continuously, the device will attempt recovery indefinitely. Refer to the ATS19520 Safety Manual for additional details on the ASIL Safe State Output Protocol.

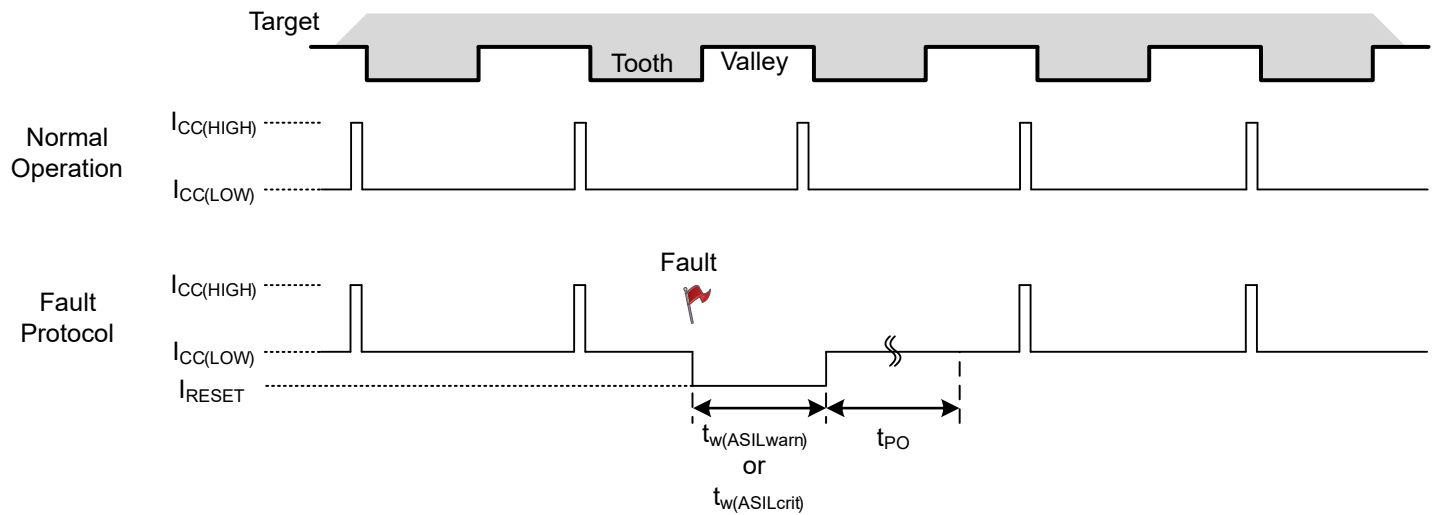


Figure 11: Output Protocol (ASIL Safe State)

POWER DERATING

The device must be operated below the maximum junction temperature of the device ($T_{J(max)}$). Under certain combinations of peak conditions, reliable operation may require derating supplied power or improving the heat dissipation properties of the application. This section presents a procedure for correlating factors affecting operating T_J . (Thermal data is also available on the Allegro website.)

The Package Thermal Resistance ($R_{\theta JA}$) is a figure of merit summarizing the ability of the application and the device to dissipate heat from the junction (die), through all paths to the ambient air. Its primary component is the Effective Thermal Conductivity (K) of the printed circuit board, including adjacent devices and traces. Radiation from the die through the device case ($R_{\theta JC}$) is relatively small component of $R_{\theta JA}$. Ambient air temperature (T_A) and air motion are significant external factors, damped by overmolding.

The effect of varying power levels (Power Dissipation, P_D), can be estimated. The following formulas represent the fundamental relationships used to estimate T_J , at P_D .

$$P_D = V_{IN} \times I_{IN} \quad (1)$$

$$\Delta T = P_D \times R_{\theta JA} \quad (2)$$

$$T_J = T_A + \Delta T \quad (3)$$

For example, given common conditions such as: $T_A = 25^\circ\text{C}$, $V_{CC} = 12\text{ V}$, $I_{CC} = 14\text{ mA}$, and $R_{\theta JA} = 150^\circ\text{C/W}$, then:

$$P_D = V_{CC} \times I_{CC} = 12\text{ V} \times 14\text{ mA} = 168\text{ mW}$$

$$\Delta T = P_D \times R_{\theta JA} = 168\text{ mW} \times 150^\circ\text{C/W} = 25.2^\circ\text{C}$$

$$T_J = T_A + \Delta T = 25^\circ\text{C} + 25.2^\circ\text{C} = 50.2^\circ\text{C}$$

A worst-case estimate, $P_{D(max)}$, represents the maximum allowable power level ($V_{CC(max)}$, $I_{CC(max)}$), without exceeding $T_{J(max)}$, at a selected $R_{\theta JA}$ and T_A .

Example: Reliability for V_{CC} at $T_A = 150^\circ\text{C}$, package SN, using a single-layer PCB.

Observe the worst-case ratings for the device, specifically:

$R_{\theta JA} = 150^\circ\text{C/W}$, $T_{J(max)} = 165^\circ\text{C}$, $V_{CC(max)} = 24\text{ V}$, and $I_{CC(avg)} = 14.6\text{ mA}$. $I_{CC(avg)}$ is computed using $I_{CC(LOW)(max)}$ and $I_{CC(HIGH)(max)}$, with a duty cycle of 83% computed from $t_{w(REV)(max)}$ on-time at 4 kHz maximum operating frequency.

Calculate the maximum allowable power level, $P_{D(max)}$. First, invert equation 3:

$$\Delta T_{max} = T_{J(max)} - T_A = 165^\circ\text{C} - 150^\circ\text{C} = 15^\circ\text{C}$$

This provides the allowable increase to T_J resulting from internal power dissipation. Then, invert equation 2:

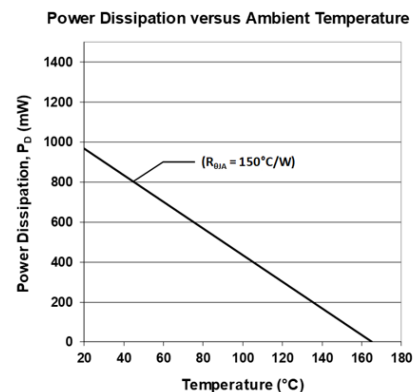
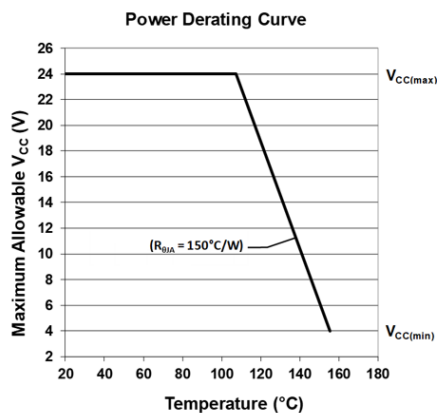
$$P_{D(max)} = \Delta T_{max} \div R_{\theta JA} = 15^\circ\text{C} \div 150^\circ\text{C/W} = 100\text{ mW}$$

Finally, invert equation 1 with respect to voltage:

$$V_{CC(est)} = P_{D(max)} \div I_{CC(avg)} = 100\text{ mW} \div 14.6\text{ mA} = 6.8\text{ V}$$

The result indicates that, at T_A , the application and device cannot dissipate adequate amounts of heat at operating voltages above 6.8 V at 150°C .

Compare $V_{CC(est)}$ to $V_{CC(max)}$. If $V_{CC(est)} \leq V_{CC(max)}$, then reliable operation between $V_{CC(est)}$ and $V_{CC(max)}$ requires enhanced $R_{\theta JA}$. If $V_{CC(est)} \geq V_{CC(max)}$, then operation between $V_{CC(est)}$ and $V_{CC(max)}$ is reliable under these conditions.



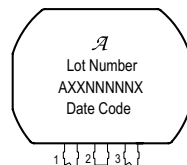
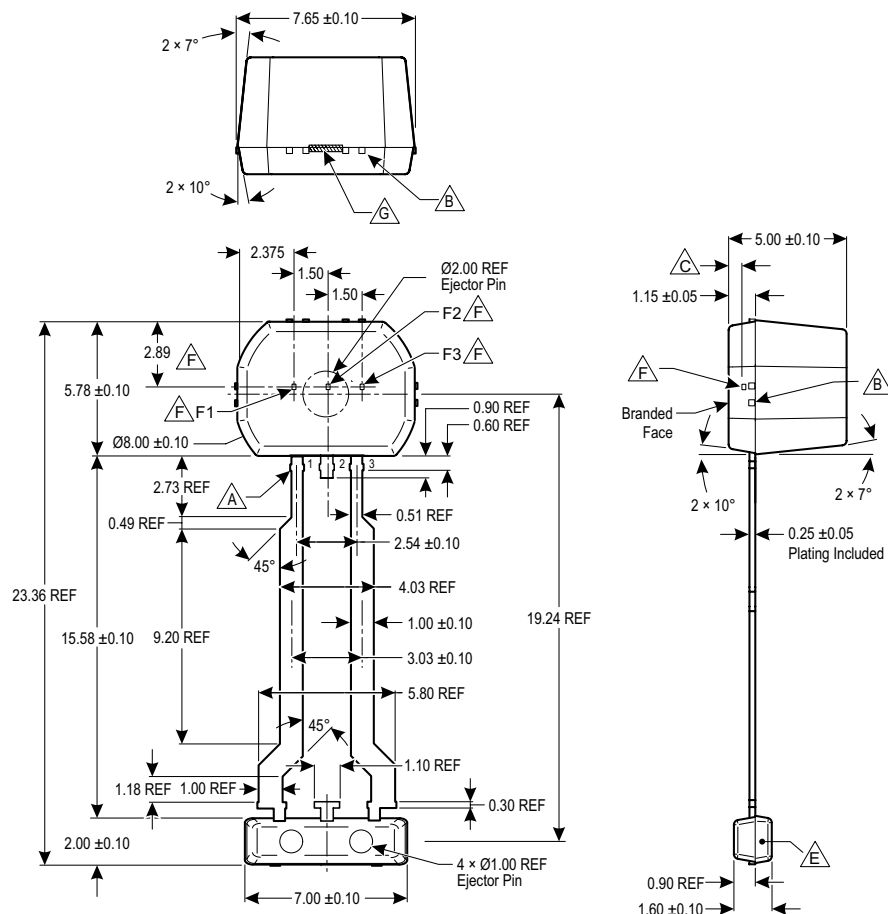
PACKAGE OUTLINE DRAWING

For Reference Only – Not for Tooling Use

(Reference DWG-0000429, Rev. 4)

Dimensions in millimeters – NOT TO SCALE

Dimensions exclusive of mold flash, gate burrs, and dambar protrusions
Exact case and lead configuration at supplier discretion within limits shown



Standard Branding Reference View

Lines 1, 2, 3, 4: Up to 10 characters, centered

Line 1: Logo A

Line 2: Characters 5, 6, 7, 8, 9, 10, 11 of
Assembly Lot Number

Line 3: 3 Character Prefix, 5 Digit Part Number,
Package Variant

Line 4: 4 digit Date Code

Notes:

- Dambar removal protrusion (12x)
- Tie bars (8x)
- Active Area Depth, 0.40 ±0.05 mm
- Branding scale and appearance at supplier discretion
- Molded lead bar for preventing damage to leads during shipment
- Hall elements (F1, F2, F3); not to scale
- Gate location

Figure 12: Package SN, 3-Pin SIP

Revision History

Number	Date	Description
–	January 31, 2019	Initial release
1	March 29, 2019	Updated Features and Benefits (page 1), selection guide (page 2), and ASIL Protocol section (page 10).
2	April 5, 2019	Updated ASIL status (page 1) and figure references (page 4).
3	October 15, 2020	Updated Operate and Release Point values (page 6).
4	March 26, 2021	Updated ASIL status (page 1).
5	June 19, 2024	Added First Direction-Pulse Output Following Direction Change and First Direction-Pulse Output Following Running Mode Vibration characteristics (page 6).
6	April 10, 2025	Updated A ² -SIL logo and descriptions (page 1), modified selection guide illustration (page 2), modified operating characteristic footnotes (pages 5 and 6), removed timer period characteristic (page 6), and reformatted document for interactive PDF capability (all pages).
7	October 27, 2025	Updated Vibration Immunity and First Direction-Pulse Output Following Running Mode Vibration characteristics (page 6); added sections Startup Detection/Calibration (page 10) and Vibration Immunity and Direction Detection (page 11).

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